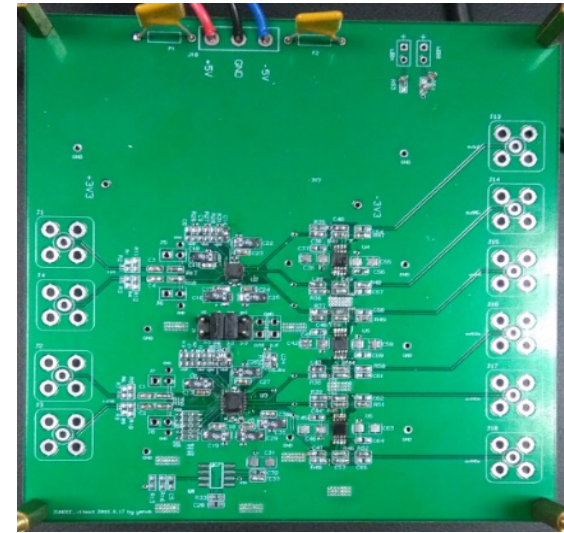
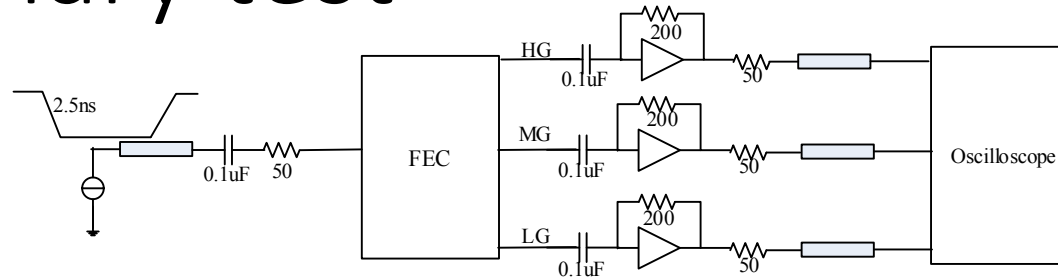


# FEC and front-end protection progress

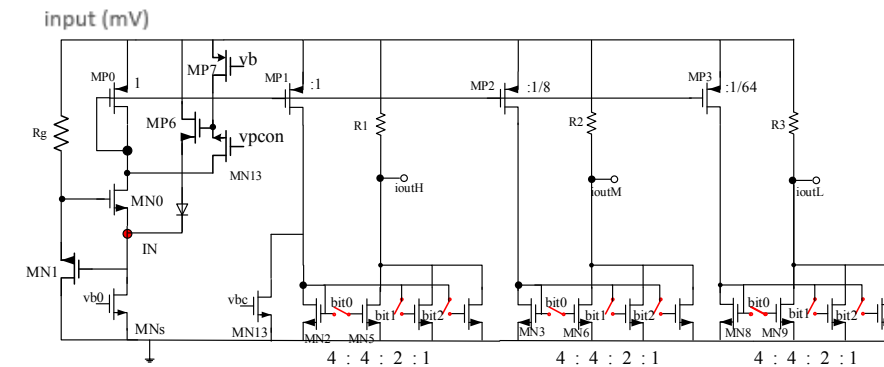
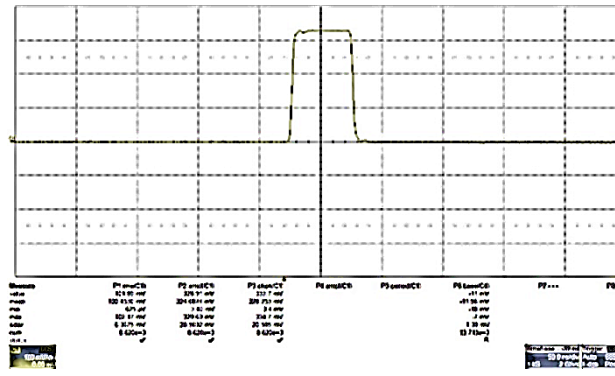
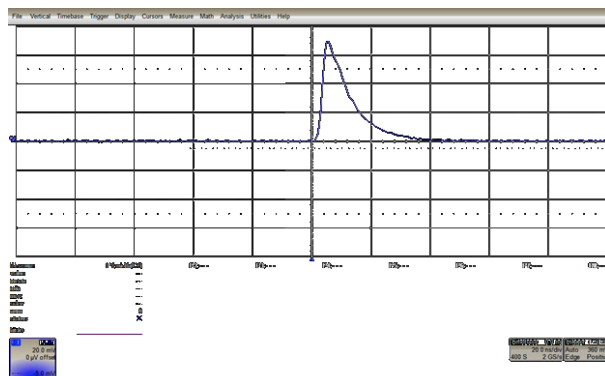
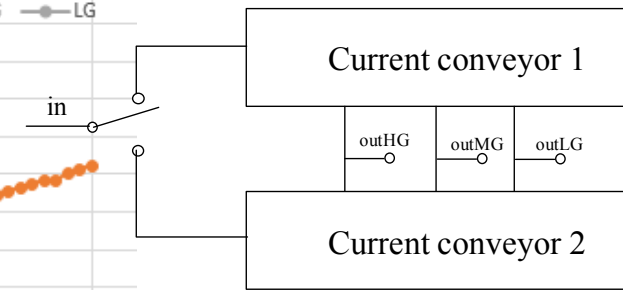
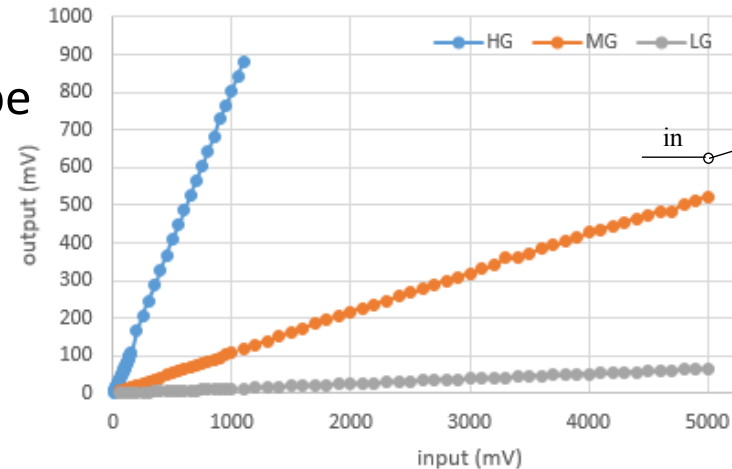
YAN X.B, Tang F.K, ZHAO T.C

# FEC\_V1 preliminary test

- Redundant design of FEC
- Gain adjustment in case PMT degeneration
- Followed by TIA to increase output current swing
- Input impedance of about 5Ω
- RMS noise equivalent to input 3uA while 120uA for 1 pe
- HG, MG covers whole dynamic range and linearity is acceptable, change LG for HG Redundancy is possible
- Not test to 7.5V input blame to the generator, neither in-chip over current protection
- Difference between not studied carefully



FEC linearity



# MCP-PMT modeling & simulation

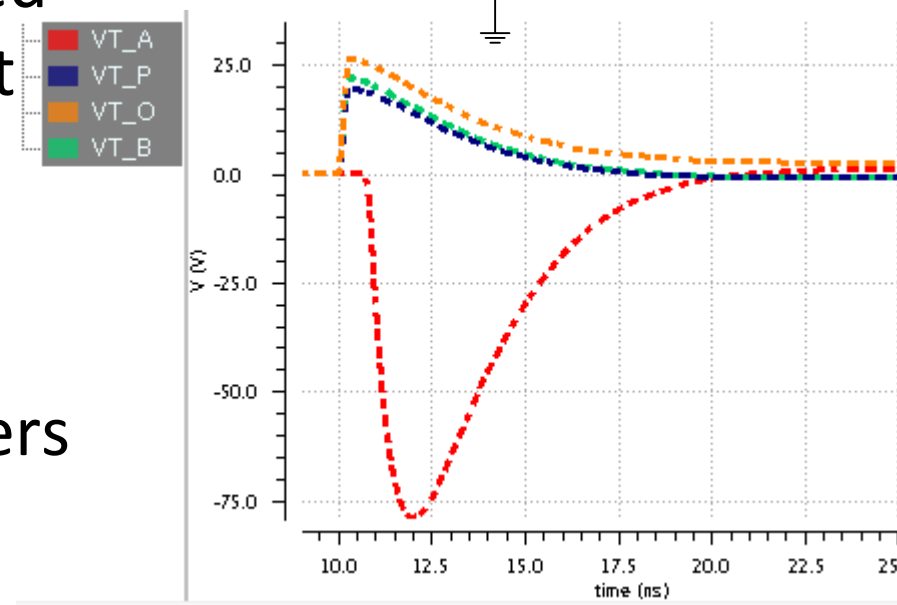
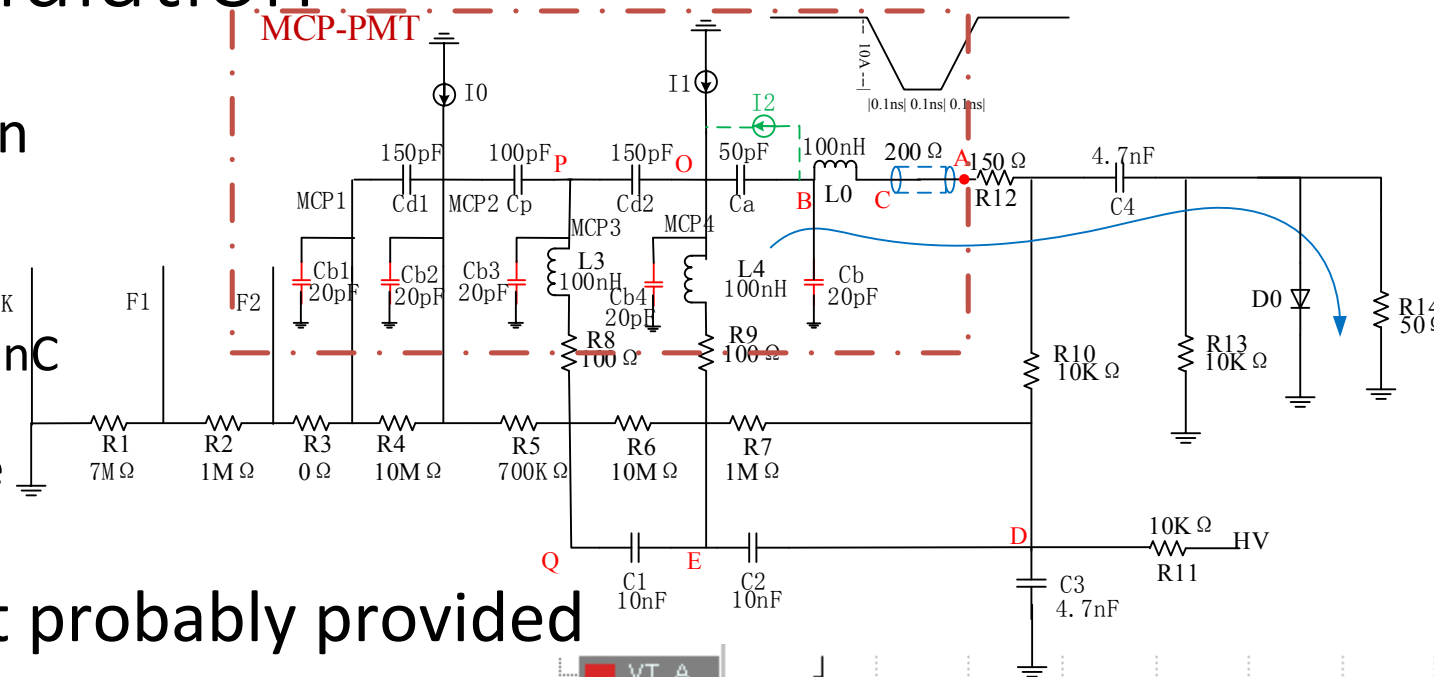
- Hope to find solution of current limitation

- MCP-PMT model:

- Only last MCP is considered due to the gain  $K$
- MCP presented as Current Source ( $I_1$ ) of  $2\text{nC}$  Charge ( $1\text{pe} \cdot 10^7 = 1.6\text{nC}$ )
- Parasitic  $20\text{pF}, 100\text{nH}$  at the end of electrode
- Base of positive HV

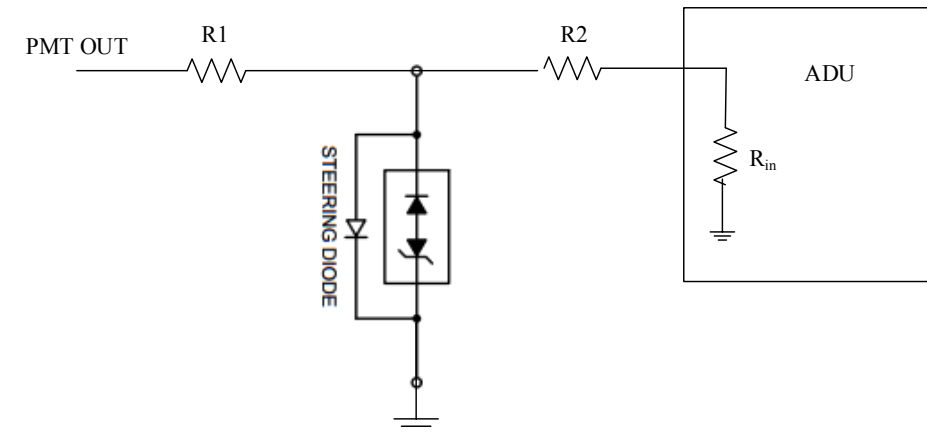
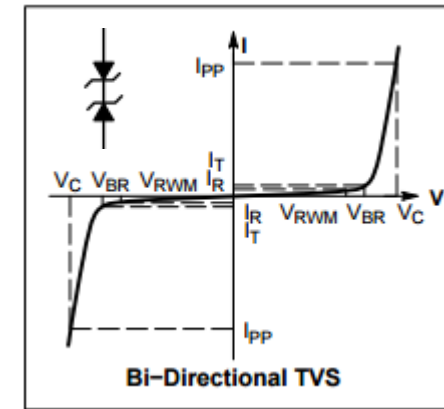
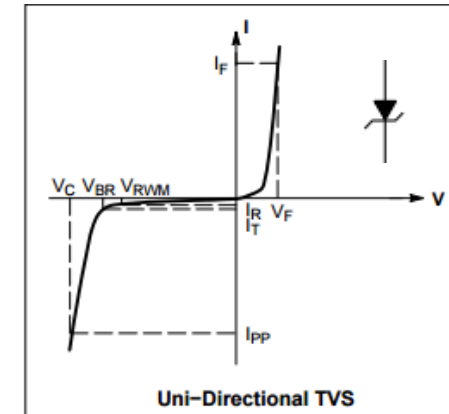
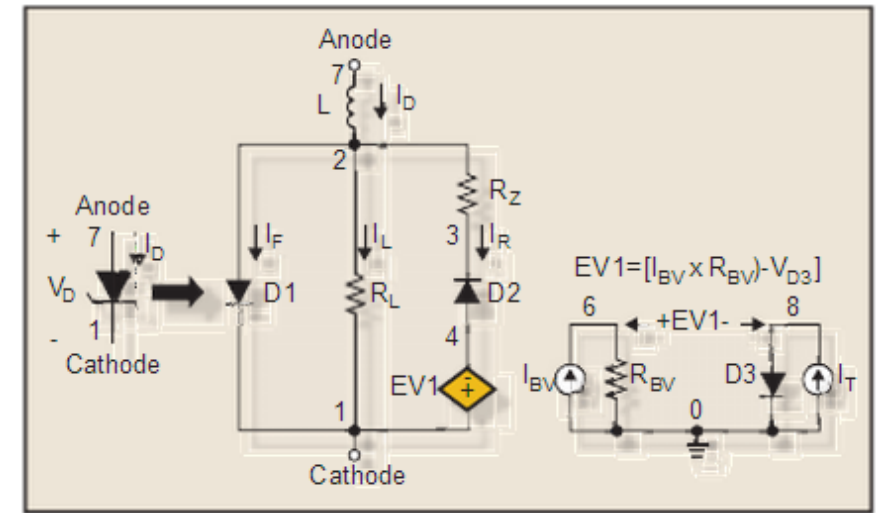
- MCP signal happens, Charge most probably provided by parasitic capacitors very fast, then electrons drift to anode, mainly discharged from output.

- Front edge comes from (L/R), falling edge (CR)
- Potential between electrodes not significant changed, no idea for limiting from divider parameters
- Diode used for protection

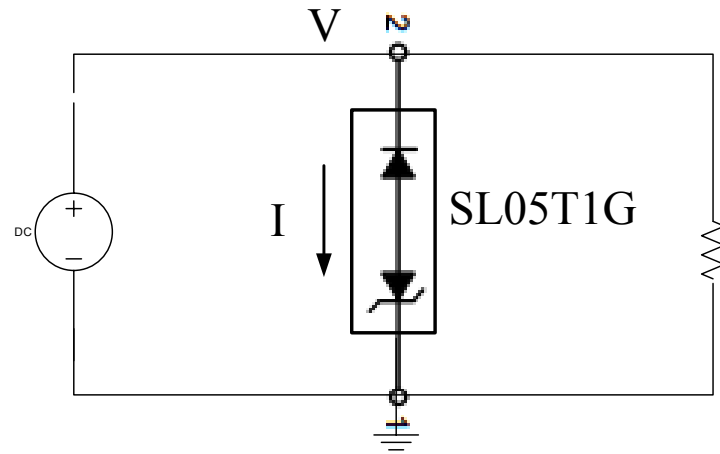


# Protection

- TVS (Transient Voltage Suppressor) has very good performance of transient voltage protection
  - $V_{RWM} \approx 0.8 * V_{BR}$ ,
  - $I_{pp}$  up to several Ampere
  - $P_{pk}$  up to hundreds Walt
  - very fast response time ( $<1ns$ )
- Uni-directional TVS has forward voltage around 0.6V
- Bi-Directional protection needed
  - TVS avalanche for negative duration
  - Fast switching steering diode for positive duration
    - $I_F$  up to 200mA,  $V_R > 70V$ , only consider overshoot
    - Increment of capacitance effect to bandwidth
  - Different clamping voltage for different polarity
  - Reliability not considered carefully
    - Shorted or open when failed?

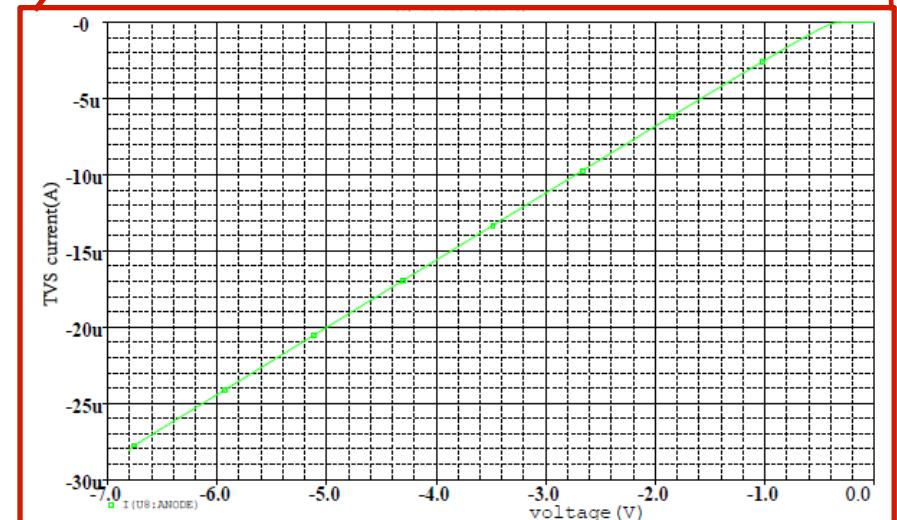
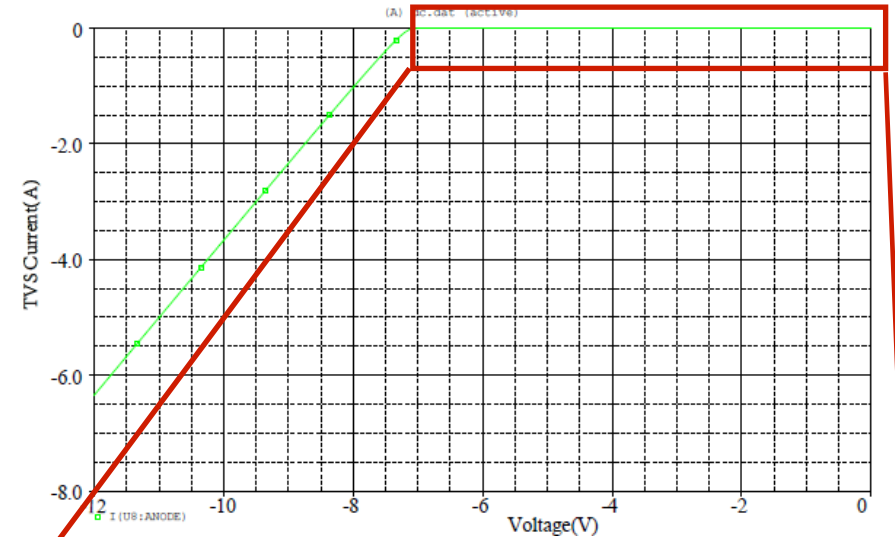


# SL05T1G spice model simulation—DC scan

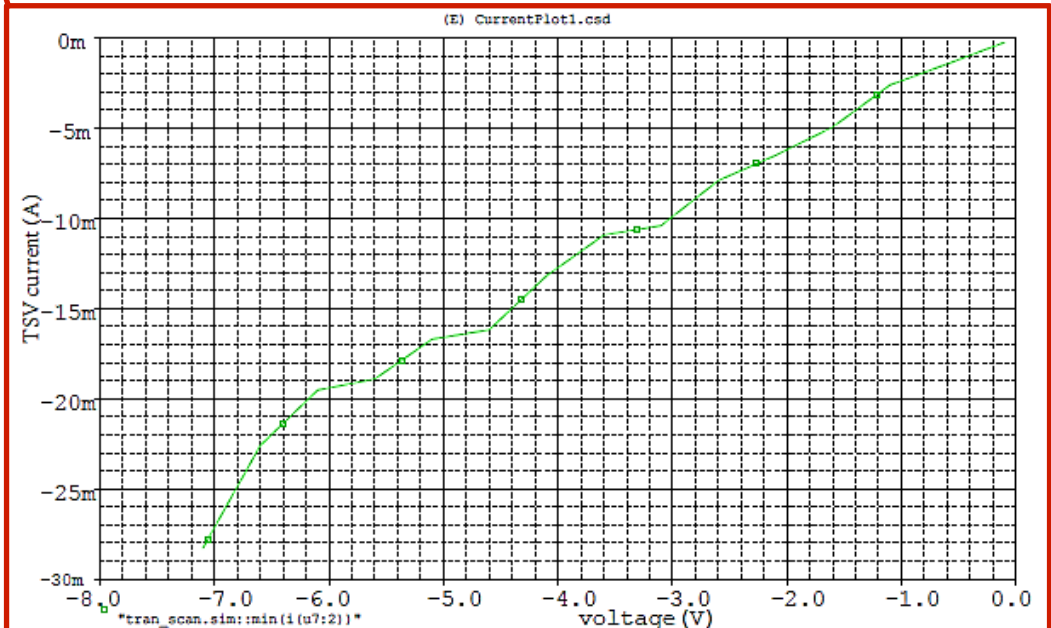
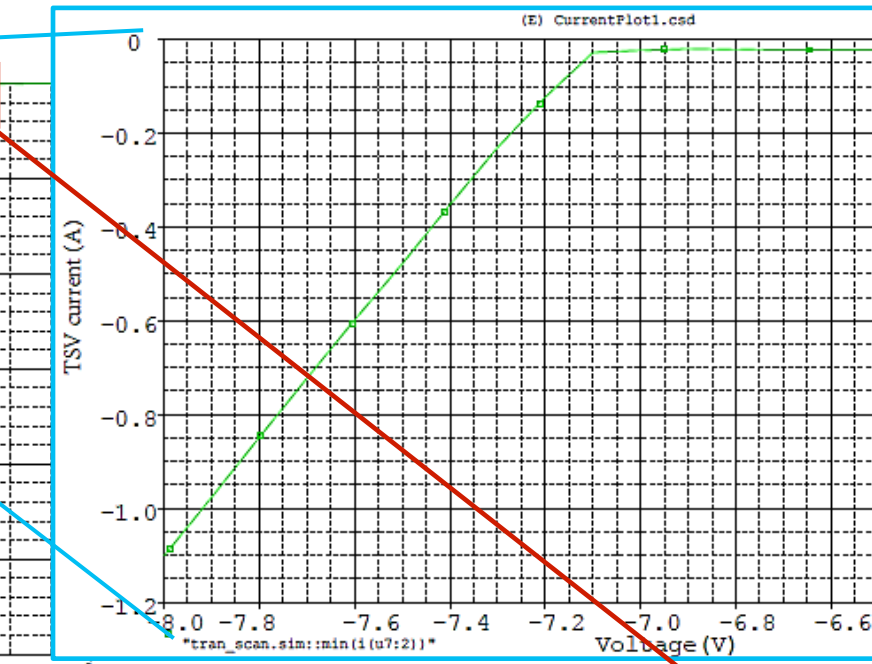
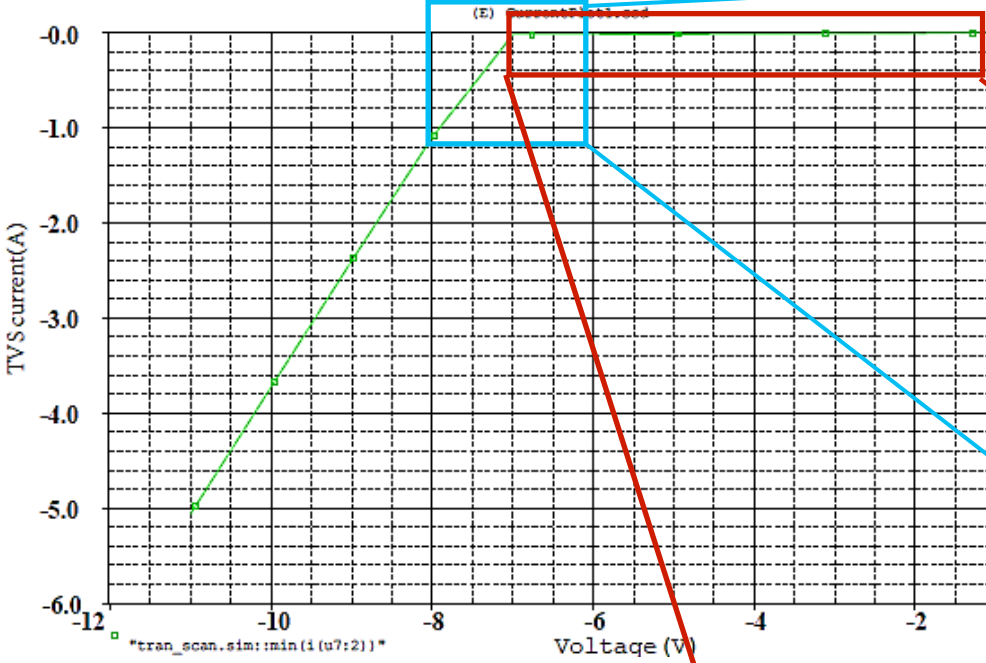
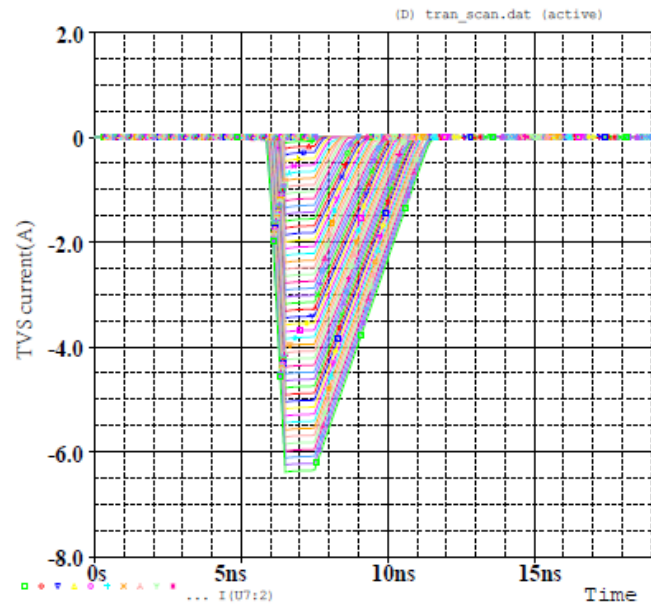


Device	Device Marking	$V_{RWM}$ (V)	$I_R$ @ $V_{RWM}$ ( $\mu$ A)	Breakdown Voltage (Note 4)		$V_C$ , Clamping Voltage (Note 5)		Max $I_{PP}$ (A)	Capacitance @ $V_R = 0$ V, 1 MHz (pF)	
				$V_{BR}$ @ 1 mA (Volts)		@ 1 A	@ 5 A		Typ	Max
				Min	Max	(V)	(V)			
SL05	L05	5.0	20	6.0	8.0	9.8	11	17	3.5	5.0

- Reverse leakage current is small,  $I_R=20\mu A@5V$
- $V_{BR}=7V @ I_{test}=1mA$
- $V_C=8V @ I_{test}=1A$ ;
- $V_C=11V @ I_{test}=5A$



# SL05T1G simulation--Transient response



- Input :  $T_r=1.5\text{ns}$ ,  $T_f=10\text{ns}$ ,  $w=1\text{ns}$
- Transient reverse performance is similar as DC reverse biased
  - $V_{BRt}=7\text{V}$  @  $I_{testt}=28\text{mA}$ ,  $I_{testt}=0.5\text{A}$  @  $V_{ct}=7.5\text{V}$
  - Before avalanche, equivalent to a capacitor of about 5pF (or  $Z=300$ )

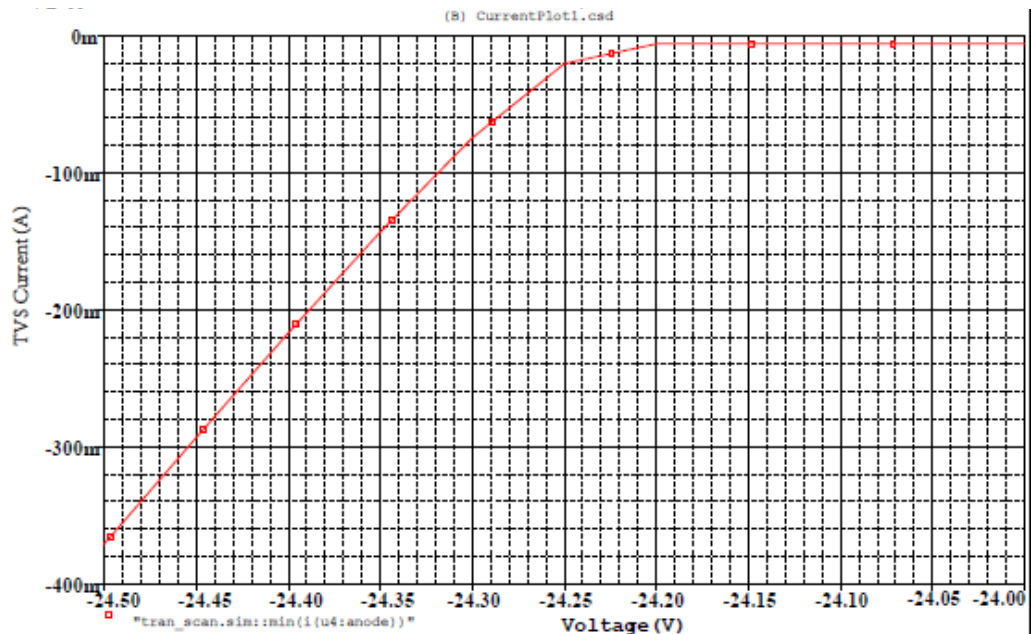
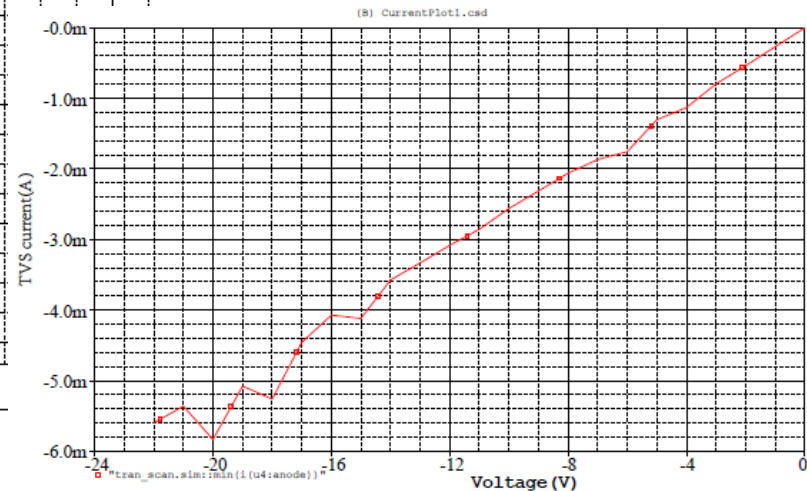
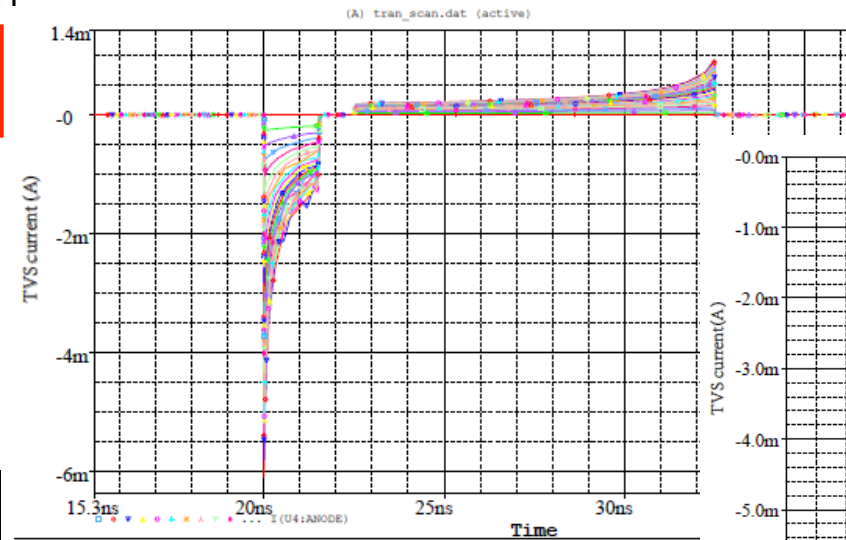
# ESD7361HT1G simulation—transient response

ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Reverse Working Voltage	$V_{RWM}$			5	16	V
Breakdown Voltage	$V_{BR}$	$I_T = 1 \text{ mA}$ ; pin 1 to pin 2	16.5			V
Reverse Leakage Current	$I_R$	$V_{RWM} = 5.0 \text{ V}$		<1	1000	nA
Clamping voltage (Note 2)	$V_C$	$I_{PP} = 8 \text{ A}$		31		V
Clamping Voltage (Note 2)	$V_C$	$I_{PP} = 16 \text{ A}$		34		V
Junction Capacitance	$C_J$	$V_R = 0 \text{ V}$ , $f = 1 \text{ MHz}$ $V_R = 0 \text{ V}$ , $f < 1 \text{ GHz}$			0.55 0.55	pF
Dynamic Resistance	$R_{DYN}$	TLP Pulse		0.735		$\Omega$
Insertion Loss		$f = 1 \text{ MHz}$ $f = 5 \text{ GHz}$		0.01 2		dB

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- For test procedure see Figures 9 and 10 and application note AND8307/D.
- ANSI/ESD STM5.5.1 – Electrostatic Discharge Sensitivity Testing using Transmission Line Pulse (TLP) Model.  
TLP conditions:  $Z_0 = 50 \Omega$ ,  $t_p = 100 \text{ ns}$ ,  $t_r = 4 \text{ ns}$ , averaging window;  $t_1 = 30 \text{ ns}$  to  $t_2 = 60 \text{ ns}$ .



- Transient performance is similar as DC reverse biased
  - Before avalanche equivalent to a capacitor of around 0.5 pF (or  $Z=4K$ ), higher  $Z$  than SL05, less signal loss
  - $V_{BRt} = 24.2 \text{ V}$ ,  $I_{testt} = 6 \text{ mA}$ ,  $I_{testt} = 0.4 \text{ A}$  @  $V_{ct} = 24.5 \text{ V}$  while having mini  $V_{BR} = 16.5 \text{ V}$
  - Without typical  $V_{BR}$ , not know variation, how to select?

# conclusion

- FEC preliminary result meets the basic requirement, test not finished----New package, and improvement
- MCP-PMT model need to be verified by experiment and refinement
- TVS with Higher  $V_{BR}$  is better for protection, need testing and selecting
-